

Search Notes

Application/Control No.

10/617,322

Examiner

Tianjie Chen

Applicant(s)/Patent under
Reexamination

DINAN ET AL.

Art Unit

2652

SEARCHED

Class	Subclass	Date	Examiner
Updated		7/11/2005	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR